Search Notes

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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/629,777	YOSHIKAWA, MASAHIRO	
Examiner my wr	Art Unit	
Tod T. Van Roy	2828	

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Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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